

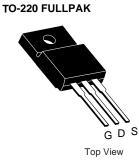
KF7N80F-VB Datasheet

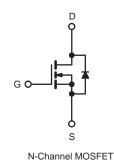
N-Channel 800V (D-S) Super Junction Power MOSFET

PRODUCT SUMMA	RY				
V _{DS} (V)	800				
R _{DS(on)} (Ω)	$V_{GS} = 10 V$	1.2			
Q _g (Max.) (nC)	200)			
Q _{gs} (nC)	24				
Q _{gd} (nC)	110)			
Configuration	Sing	le			

FEATURES

- Dynamic dV/dt Rating
- Repetitive Avalanche Rated
- Isolated Central Mounting Hole
- · Fast Switching
- Ease of Paralleling
- Simple Drive Requirements
- Compliant to RoHS Directive 2002/95/EC





ABSOLUTE MAXIMUM RATINGS (T C	= 25 °C, unl	ess otherwis	se noted)		
PARAMETER		SYMBOL	LIMIT	UNIT	
Drain-Source Voltage		V _{DS}	800	v	
Gate-Source Voltage			V _{GS}		
Continuous Drain Current	V _{GS} at 10 V	T _C = 25 °C	l-	5	
Continuous Drain Current		T _C = 100 °C	I _D	3.9	A
sed Drain Current ^a		I _{DM}	21		
Linear Derating Factor			1.5	W/°C	
Single Pulse Avalanche Energy ^b		E _{AS}	770	mJ	
Repetitive Avalanche Current ^a			I _{AR}	7.8	A
Repetitive Avalanche Energy ^a		E _{AR}	19	mJ	
Maximum Power Dissipation T _C = 25 °C		PD	190	W	
Peak Diode Recovery dV/dt ^c		dV/dt	2.0	V/ns	
perating Junction and Storage Temperature Range		T _J , T _{stg}	- 55 to + 150	°C	
Soldering Recommendations (Peak Temperature)	for	10 s		300 ^d	
Mounting Torquo	6-32 or M3 screw			10	lbf ∙ in
Mounting Torque				1.1	N · m

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. V_{DD} = 50 V, starting T_J = 25 °C, L = 23 mH, R_g = 25 Ω , I_{AS} = 7.8 A (see fig. 12). c. I_{SD} \leq 7.8 A, dl/dt \leq 140 A/µs, V_{DD} \leq 600 V, T_J \leq 150 °C.

d. 1.6 mm from case.

* Pb containing terminations are not RoHS compliant, exemptions may apply

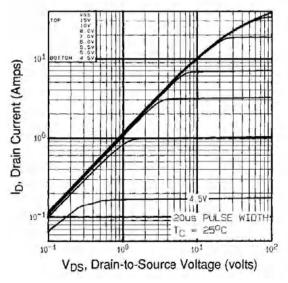


THERMAL RESISTANCE RATII	NGS							
PARAMETER	SYMBOL	TYP.		MAX.			UNIT	
Maximum Junction-to-Ambient	R _{thJA}	-		40				
Case-to-Sink, Flat, Greased Surface	R _{thCS}	0.24 - - 0.65			°C/W			
Maximum Junction-to-Case (Drain)	R _{thJC}							
		. N						
SPECIFICATIONS ($T_J = 25 \text{ °C}$, u					[1	1
PARAMETER	SYMBOL	TES	T CONDIT	IONS	MIN.	TYP.	MAX.	UNIT
Static					1	1	1	1
Drain-Source Breakdown Voltage	V _{DS}		= 0 V, I _D =		800	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Referenc	e to 25 °C,	$I_D = 1 \text{ mA}$	-	0.98	-	V/°C
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} =	= V_{GS} , I_D =	250 µA	2.0	-	4.0	V
Gate-Source Leakage	I _{GSS}		$V_{GS} = \pm 20$		-	-	± 100	nA
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} =	= 800 V, V _C	_{as} = 0 V	-	-	100	ıΔ
	220	$V_{DS} = 640 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 125 \text{ °C}$		-	-	500	V nA μA Ω S PF nC ns nH	
Drain-Source On-State Resistance	R _{DS(on)}	$V_{GS} = 10 V$	Ic	₀ = 3.7 A ^b	-	1.2	-	Ω
Forward Transconductance	g fs	V _{DS} =	= 100 V, I _D =	= 3.7 A ^b	5.6	-	-	S
Dynamic								
Input Capacitance	C _{iss}		V _{GS} = 0 V	1	-	3100	-	
Output Capacitance	C _{oss}	1	$V_{DS} = 25$	V,	-	800	-	pF
Reverse Transfer Capacitance	C _{rss}	f – 10 MHz see fig 5		490	-	1		
Total Gate Charge	Qg				-	-	200	
Gate-Source Charge	Q _{gs}	V _{GS} = 10 V		A, $V_{DS} = 400 V$, iq. 6 and 13 ^b	-	-	24	nC
Gate-Drain Charge	Q _{gd}	1	3001	ig. o and to	-	-	110	
Turn-On Delay Time	t _{d(on)}				-	19	-	
Rise Time	t _r		= 400 V, I _D		-	38	-	
Turn-Off Delay Time	t _{d(off)}	R _g =	= 6.2 Ω, R _D see fig. 10	= 52 Ω nb	-	120	-	ns
Fall Time	t _f		see lig. It		-	39	-	
Internal Drain Inductance	L _D	Between lead 6 mm (0.25") f	from		-	5.0	-	
Internal Source Inductance	L _S	package and die contact	center of		-	13	-	nH
Drain-Source Body Diode Characteristic	S							
Continuous Source-Drain Diode Current	I _S	MOSFET sym showing the	bol		-	-	5.0	Δ
Pulsed Diode Forward Current ^a	I _{SM}	integral revers p - n junction			-	-	21	
Body Diode Voltage	V _{SD}	T _J = 25 °C	C, I _S = 3.8 A	A, $V_{GS} = 0 V^{b}$	-	-	1.8	V
Body Diode Reverse Recovery Time	t _{rr}	T.=	25 °C, I _F =	: 3.8 A.	-	650	980	ns
Body Diode Reverse Recovery Charge	Q _{rr}	dl	/dt = 100 A	õs ^b	-	3.8	5.7	μC
Forward Turn-On Time	t _{on}	Intrinsic tu	rn-on time	is negligible (turn	-on is do	ninated h	v Ls and	L _D)

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
b. Pulse width ≤ 300 µs; duty cycle ≤ 2 %.





TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



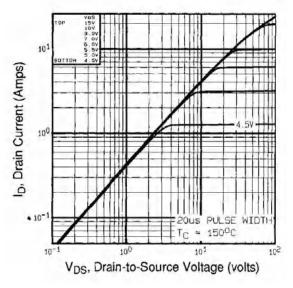


Fig. 2 - Typical Output Characteristics, $T_C = 150$ °C

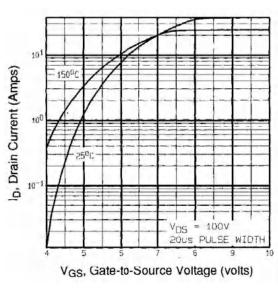
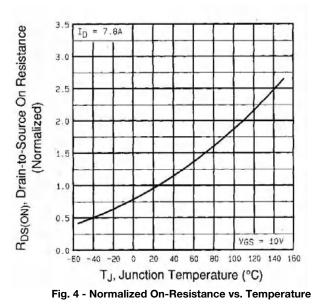


Fig. 3 - Typical Transfer Characteristics





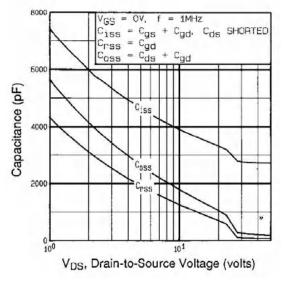


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

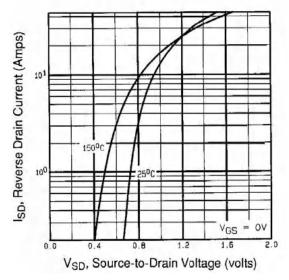


Fig. 7 - Typical Source-Drain Diode Forward Voltage

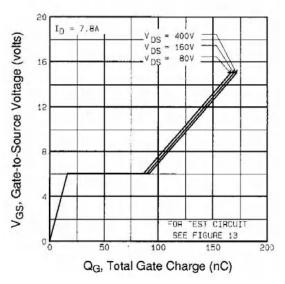
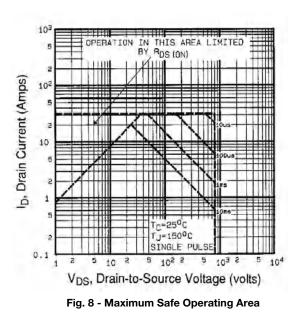


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage





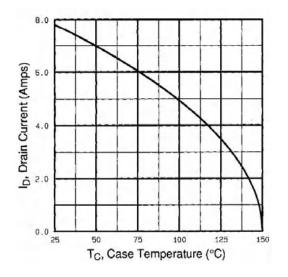


Fig. 9 - Maximum Drain Current vs. Case Temperature

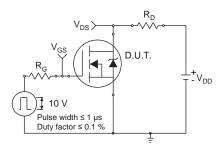


Fig. 10a - Switching Time Test Circuit

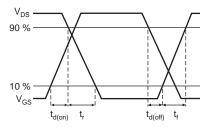


Fig. 10b - Switching Time Waveforms

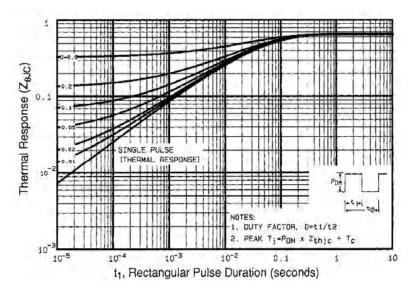


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case



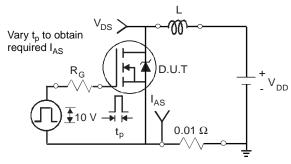


Fig. 12a - Unclamped Inductive Test Circuit

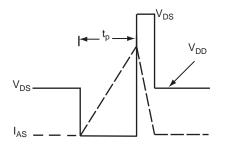


Fig. 12b - Unclamped Inductive Waveforms

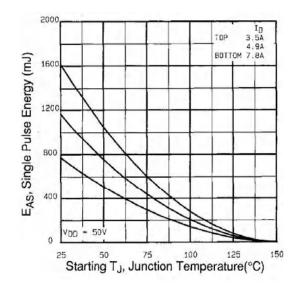


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

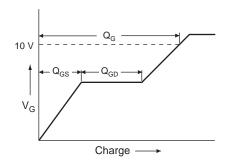
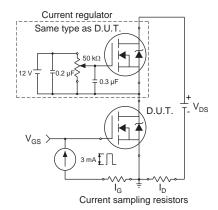


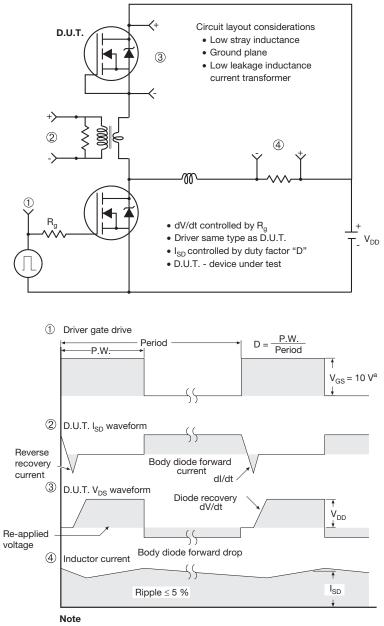
Fig. 13a - Basic Gate Charge Waveform







Peak Diode Recovery dV/dt Test Circuit

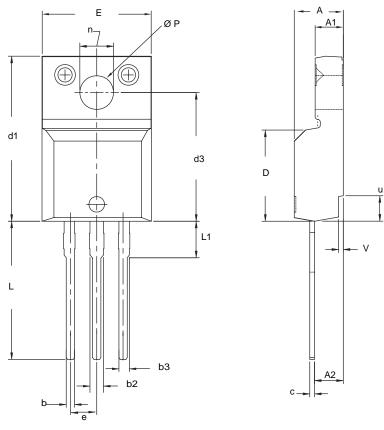


a. $V_{GS} = 5 V$ for logic level devices

Fig. 14 - For N-Channel



TO-220 FULLPAK (HIGH VOLTAGE)



DIM.	MILLI	METERS	INC	CHES	
	MIN.	MAX.	MIN.	MAX.	
А	4.570	4.830	0.180	0.190	
A1	2.570	2.830	0.101	0.111	
A2	2.510	2.850	0.099	0.112	
b	0.622	0.890	0.024	0.035	
b2	1.229	1.400	0.048	0.055	
b3	1.229	1.400	0.048	0.055	
С	0.440	0.629	0.017	0.025	
D	8.650	9.800	0.341	0.386	
d1	15.88	16.120	0.622	0.635	
d3	12.300	12.920	0.484	0.509	
E	10.360	10.630	0.408	0.419	
е	2.54	BSC	0.100 BSC		
L	13.200	13.730	0.520	0.541	
L1	3.100	3.500	0.122	0.138	
n	6.050	6.150	0.238	3 0.242	
ØP	3.050	3.450	0.120 0.1		
u	2.400	2.500 0.094		0.098	
V	0.400	0.500	0.016	0.020	

Notes

1. To be used only for process drawing. 2. These dimensions apply to all TO-220, FULLPAK leadframe versions 3 leads. 3. All critical dimensions should C meet $C_{pk} > 1.33$. 4. All dimensions include burrs and plating thickness. 5. No chipping or package damage.



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